

Homework 8
Due 11 November 2003

1. For 100keV Sn ions in Si, find the approximate value of dpa (using tabulated values for ϵ and R_p) for a dose of 5×10^{13} ions/cm². This level of damage is sufficient to form an amorphous layer in Silicon.
2. Using the power law energy-transfer cross-section, calculate the approximate mean free path between Si recoils for both Si and Xe ions with energies of 1, 10, and 100keV. Refer to Section 7.11.1 of the textbook.
3. Consider the case of: 1.) Si ions incident on Au, and 2.) Au ions incident on Si; both cases for 100keV incident energies normal to the sample. Which would have the largest value of:
 - a.) the dimensionless energy ϵ
 - b.) electronic energy loss rate, $dE/dx|_e$
 - c.) nuclear energy loss rate, $dE/dx|_n$
 - d.) projected range, R_p
 - e.) sputtering yield, Y (assume a binding energy of $U = 5\text{eV}$)
 - f.) maximum concentration of implanted species
4. Calculate the energy-independent sputtering yield values of Ne, Ar, and Xe incident on Ni at 10keV using the expressions for nuclear stopping given in Chapter 5 and a binding energy of 5 eV.
 - a.) Compare you values with data given in Chapter 9 (Fig. 9.3)
 - b.) Calculate values of the dimensionless energy, ϵ , for the three cases. Are these ϵ values in a region where nuclear stopping rates would dominate?
 - c.) For a current of $10\mu\text{A}/\text{cm}^2$ of Ar, how many monolayers (10^{15} atoms/cm²) would be removed per second?